20 STERN AVE. SPRINGFIELD, NEW JERSEY 07081 U.S.A.

IRF320, IRF321, ELEPHONE: (973) 376-2922 (212) 227-6005 IRF322, IRF323

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2.8A and 3.3A, 350V and 400V, 1.8 and 2.5 Ohm, **N-Channel Power MOSFETs**

Features

- 2.8A and 3.3A, 350V and 400V
- $r_{DS(ON)} = 1.8\Omega$ and 2.5 Ω
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- · Nanosecond Switching Speeds
- · Linear Transfer Characteristics
- · High Input Impedance
- Majority Carrier Device

Description

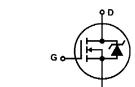
These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Symbol

Ordering Information

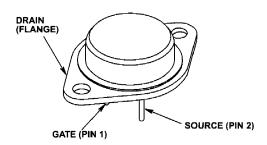
PART NUMBER	PACKAGE	BRAND
IRF320	TO-204AA	IRF320
IRF321	TO-204AA	IRF321
IRF322	TO-204AA	IRF322
IRF323	TO-204AA	IRF323

NOTE: When ordering, use the entire part number.



Packaging

JEDEC TO-204AA



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

Quality Semi-Conductors

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	IRF320	IRF321	IRF322	IRF323	UNITS
Drain to Source Breakdown Voltage (Note 1)V _{DS}	400	350	400	350	V
Drain to Gate Voltage (R _{GS} = 20kΩ) (Note 1) V _{DGR}	400	350	400	350	V
Continuous Drain CurrentIp	3.3	3.3	2.8	2.8	Α
$T_C = 100^{\circ}CI_D$	2.1	2.1	1.8	1.8	Α
Pulsed Drain Current (Note 3)	13	13	11	11	Α
Gate to Source Voltage	±20	±20	±20	±20	V
Maximum Power Dissipation	50	50	50	50	W
Linear Derating Factor	0.4	0.4	0.4	0.4	W/°C
Single Pulse Avalanche Energy Rating (Note 4) EAS	190	190	190	190	mJ
Operating and Storage Temperature T _{J,} T _{STG}	-55 to 150	-55 to 150	-55 to 150	-55 to 150	°C
Maximum Temperature for Soldering					-
Leads at 0.063in (1.6mm) from Case for 10s T _L	300	300	300	300	°C
Package Body for 10s, See TB334 T _{pkg}	260	260	260	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS		TYP	MAX	UNITS
Drain to Source Breakdown Voltage IRF320, IRF322	BV _{DSS}	I _D = 250μA, V _{GS} = 0V, (Figure 10)		-	- -	V
IRF321, IRF323			350	-	-	٧
Gate to Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D = 250μA	2.0	-	4.0	٧
Zero Gate Voltage Drain Current	l _{DSS}	V _{DS} = Rated BV _{DSS} , V _{GS} = 0V	-	-	25	μΑ
		V _{DS} = 0.8 x Rated BV _{DSS} , V _{GS} = 0V T _J = 125°C		-	250	μА
On-State Drain Current (Note 2) IRF320, IRF321	ID(ON)	V _{DS} > I _{D(ON)} × r _{DS(ON)MAX} , V _{GS} = 10V (Figure 7)		-	_	А
IRF322, IRF323			2.8	-	-	Α
Gate to Source Leakage Current	l _{GSS}	V _{GS} = ±20V			±100	nA
Drain to Source On Resistance (Note 2) IRF320, IRF321	rDS(ON)	I_D = 1.8A, V_{GS} = 10V, (Figures 8, 9) $V_{DS} \ge 10V, I_D = 2.0A, (Figure 12)$		1.5	1.8	Ω
IRF322, IRF323				1.8	2.5	Ω
Forward Transconductance (Note 2)	9fs			2.7	-	S
Turn-On Delay Time	t _d (ON)	V_{DD} = 200V, I_{D} \approx 3.3A, R_{G} = 18 Ω , R_{L} = 60 Ω , V_{GS} = 10V, (Figures 17, 18) MOSFET Switching Times are Essentially Independent of Operating Temperature		10	15	ns
Rise Time	t _r			14	20	ns
Turn-Off Delay Time	t _{d(OFF)}			30	45	ns
Fall Time	t _f			13	20	ns
Total Gate Charge (Gate to Source + Gate to Drain)	Q _{g(TOT)}	V_{GS} = 10V, I_D = 3.3A, V_{DS} = 0.8 x Rated BV _{DSS} , $I_{G(REF)}$ = 1.5mA, (Figures 14, 19, 20) Gate Charge is Essentially Independent of Operating Temperature		12	20	nC
Gate to Source Charge	Q _{gs}			4	-	nC
Gate to Drain "Miller" Charge	Q _{gd}			8	-	nC

IRF320, IRF321, IRF322, IRF323

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Input Capacitance	C _{ISS}	V _{DS} = 25V, V _{GS} = 0V, f = 1MHz (Figure 11)		-	450	-	pF
Output Capacitance	c _{oss}			-	100	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	20	-	pF
Internal Drain Inductance	LD	Measured Between the Contact Screw on the Flange that is Closer to Source and Gate Pins and the Center of Die	Modified MOSFET Symbol Showing the Internal Devices Inductances	-	5.0	-	nH
Internal Source Inductance	Ls	Measured from the Source Lead, 6mm (0.25in) From the Flange and the Source Bonding Pad	G L _D	-	12.5	-	nH
Thermal Resistance Junction to Case	R ₀ JC			-	-	2.5	°C/W
Thermal Resistance Junction to Ambient	R _{θJA}	Free Air Operation		-	-	30	°C/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	I _{SD}	Modified MOSFET	♀ D	-	-	3.3	Α
Pulse Source to Drain Current (Note 3)	ISDM	Symbol Showing the Integral Reverse P-N Junction Diode G	G S S	-	-	13	А
Source to Drain Diode Voltage (Note 2)	V _{SD}	$T_C = 25^{\circ}C$, $I_{SD} = 3.3A$, $V_{GS} = 0V$, (Figure 13)		-	-	1.8	V
Reverse Recovery Time	t _{rr}	$T_J = 25^{\circ}$ C, $I_{SD} = 3.3$ A, $dI_{SD}/dt = 100$ A/µs		120	270	600	ns
Reverse Recovery Charge	Q _{RR}	$T_J = 25^{\circ}C$, $I_{SD} = 3.3A$, $dI_{SD}/dt = 100A/\mu s$		0.64	1.4	3.0	μC

NOTES

2. Pulse test: pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$.